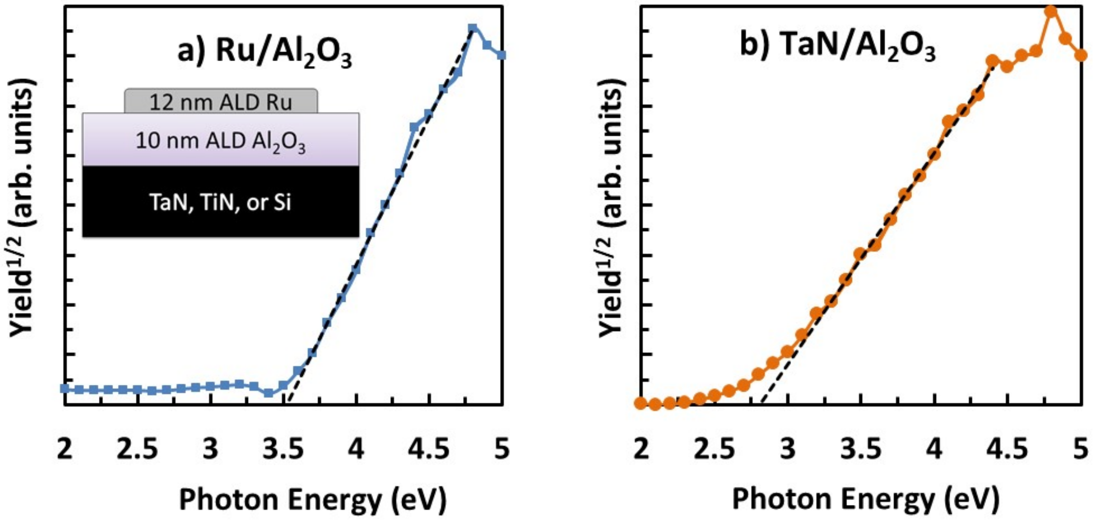

Fig. 1: Representative spectral threshold extraction for the as-deposited Ru/Al$_2$O$_3$/TaN device at the (a) Ru/Al$_2$O$_3$ interface and (b) TaN/Al$_2$O$_3$ interface.

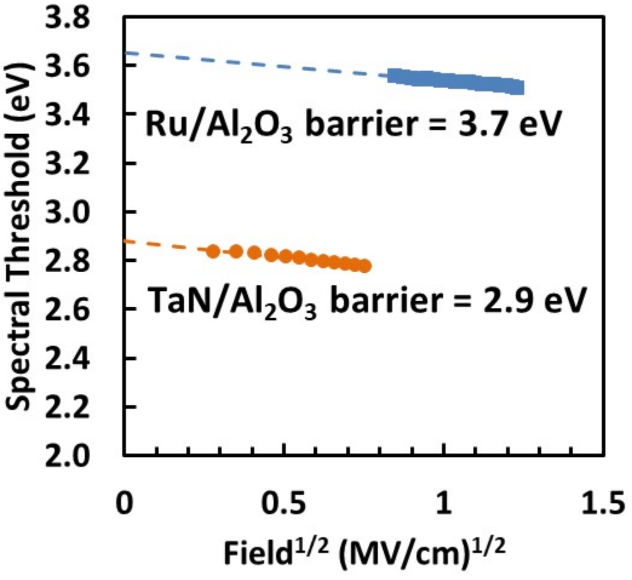

Fig. 2: Schottky plot indicating the zero-field barrier height for each interface.